comparator means for comparing the current waveforms and, when a difference between the current waveforms exceeds a predetermined value, for outputting an information related to the position on said test sample at which the difference exists.

14. (Amended) A semiconductor device test method comprising:

scanning a first test sample with an electron beam having a rectangular cross section, a longer side of which is substantially equal to a diameter of a contact hole in the first test sample, in a scan direction perpendicular to the longer side, moving the scan position by a distance equal to the diameter of the contact hole in a direction perpendicular to the scan direction every time when the scan of one line is completed and storing values of current generated in the first test sample when irradiated with the electron beam in correspondence with positions of the electron beam as a first current waveform;

scanning a second test sample with an electron beam having a rectangular cross section, a longer side of which is substantially equal to a diameter of a contact hole in the first test sample, in the scan direction, moving the scan position by a distance equal to the diameter of the contact hole in a direction perpendicular to the scan direction every time when the scan of one line is completed and storing values of current generated in the second test sample when irradiated with the electron beam in correspondence with positions of the electron beam as a second current waveform; and

comparing the first current waveform with the second current waveform and, when there is a difference exceeding a predetermined value between the first and second current waveforms, extracting coordinates of a position corresponding to the difference.

Please add new claim 26 as follows:

- - 26. (Newly Added) A semiconductor device tester comprising:

an electron beam device that irradiates a test sample with an electron beam;

a current measurer that measures current generated in said test sample by said electron beam;

a memory that stores current waveforms for each of a plurality of test samples, wherein said current waveforms comprise variations of said measured current for each of said plurality of test samples in correspondence with irradiation positions of said electron beam; and

a comparator that compares the current waveforms and, when a difference between the current waveforms exceeds a predetermined value, outputs an information related to the position on said test sample at which the difference exists. - -

REMARKS

An Excess Claim Fee Payment letter and fee for an excess independent claim is attached hereto.

Applicant thanks Examiner Nguyen for the courtesies extended to Applicant's representative during the personal interview on March 10, 2003. During the personal interview,